

Data Sheet July 1999 FN4628.1

# Radiation Hardened Octal Transparent Latch, Three-State

Intersil's Satellite Applications Flow<sup>TM</sup> (SAF) devices are fully tested and guaranteed to 100kRAD total dose. These QML Class T devices are processed to a standard flow intended to meet the cost and shorter lead-time needs of large volume satellite manufacturers, while maintaining a high level of reliability.

The Intersil HCTS373T is a Radiation Hardened Octal Transparent Three-State Latch with an active-low output enable. The outputs are transparent to the inputs when the Latch Enable ( $\overline{\text{LE}}$ ) is HIGH. When the Latch Enable ( $\overline{\text{OE}}$ ) goes LOW, the data is latched. The Output Enable ( $\overline{\text{OE}}$ ) controls the three-state outputs. When the Output Enable ( $\overline{\text{OE}}$ ) is HIGH, the outputs are in the high impedance state. The latch operation is independent of the state of the Output Enable.

# **Specifications**

Specifications for Rad Hard QML devices are controlled by the Defense Supply Center in Columbus (DSCC). The SMD numbers listed below must be used when ordering.

Detailed Electrical Specifications for the HCTS373T are contained in SMD 5962-95747. A "hot-link" is provided from our website for downloading.

www.intersil.com/spacedefense/newsafclasst.asp

Intersil's Quality Management Plan (QM Plan), listing all Class T screening operations, is also available on our website.

www.intersil.com/quality/manuals.asp

# **Ordering Information**

ORDERING NUMBER	PART NUMBER	TEMP. RANGE (°C)
5962R9574701TRC	HCTS373DTR	-55 to 125
5962R9574701TXC	HCTS373KTR	-55 to 125

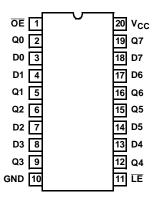
NOTE: Minimum order quantity for -T is 150 units through distribution, or 450 units direct.

#### **Features**

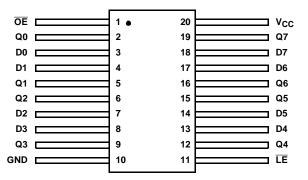
- QML Class T, Per MIL-PRF-38535
- Radiation Performance
  - Gamma Dose (y) 1 x 10<sup>5</sup> RAD(Si)
  - Latch-Up Free Under Any Conditions
  - SEP Effective LET No Upsets: >100 MEV-cm<sup>2</sup>/mg
  - Single Event Upset (SEU) Immunity < 2 x 10<sup>-9</sup> Errors/Bit-Day (Typ)
- · 3 Micron Radiation Hardened CMOS SOS
- Fanout (Over Temperature Range)
  - Bus Driver Outputs 15 LSTTL Loads
- Significant Power Reduction Compared to LSTTL ICs
- DC Operating Voltage Range: 4.5V to 5.5V
- LSTTL Input Compatibility
  - V<sub>IL</sub> = 0.8V Max
  - V<sub>IH</sub> = V<sub>CC/2</sub> Min
- Input Current Levels Ii ≤ 5mA at V<sub>OI</sub>, V<sub>OH</sub>

### **Pinouts**

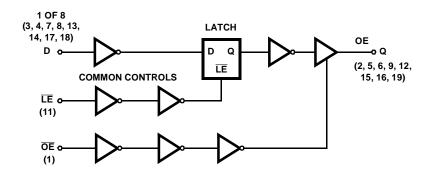
#### HCTS373T (SBDIP), CDIP2-T20 TOP VIEW



#### HCTS373T (FLATPACK), CDFP4-F20 TOP VIEW



# Functional Diagram



#### **TRUTH TABLE**

ŌĒ	LE	D	Q
L	Н	Н	Н
L	Н	L	L
L	L	I	L
L	L	h	Н
Н	Х	X	Z

H = High Level, L = Low Level.

X = Immaterial, Z = High Impedance.

 $I = Low\ voltage\ level\ prior\ to\ the\ high-to-low\ latch\ enable\ transition.$ 

h = High voltage level prior to the high-to-low latch enable transition.

#### Die Characteristics

**DIE DIMENSIONS:** 

 $(2743 \mu m \ x \ 2692 \mu m \ x \ 533 \mu m \ \pm 51 \mu m)$ 

108 x 106 x 21mils ±2mil

**METALLIZATION:** 

Type: Al Si

Thickness: 11kÅ ±1kÅ

**SUBSTRATE POTENTIAL:** 

Unbiased (Silicon on Sapphire)

**BACKSIDE FINISH:** 

Sapphire

PASSIVATION:

Type: Silox (S<sub>i</sub>O<sub>2</sub>)

Thickness: 13kÅ ±2.6kÅ

WORST CASE CURRENT DENSITY:

< 2.0e5 A/cm<sup>2</sup>

TRANSISTOR COUNT:

376

PROCESS:

**CMOS SOS** 

# Metallization Mask Layout

### HCTS373T ŌΕ D0 Q0 Q7 V<sub>CC</sub> (3) (19) (2) (1) (20)(18) D7 D1 (4) (17) D6 Q1 (5) (16) Q6 Q2 (6) (15) Q5 D2 (7) (14) D5 (8) (9) (10)(11)(12)(13)D3 Q3 GND ĪĒ

NOTE: The die diagram is a generic plot from a similar HCS device. It is intended to indicate approximate die size and bond pad location. The mask series for the HCTS373 is TA14403A.

All Intersil U.S. products are manufactured, assembled and tested utilizing ISO9000 quality systems. Intersil Corporation's quality certifications can be viewed at www.intersil.com/design/quality

Intersil products are sold by description only. Intersil Corporation reserves the right to make changes in circuit design, software and/or specifications at any time without notice. Accordingly, the reader is cautioned to verify that data sheets are current before placing orders. Information furnished by Intersil is believed to be accurate and reliable. However, no responsibility is assumed by Intersil or its subsidiaries for its use; nor for any infringements of patents or other rights of third parties which may result from its use. No license is granted by implication or otherwise under any patent or patent rights of Intersil or its subsidiaries.

For information regarding Intersil Corporation and its products, see www.intersil.com